



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Shin FUJITA

Group Art Unit: 2829

Application No.: 09/994,675

Examiner: Trung Q. Nguyen

Filed: November 28, 2001

Docket No.: 110954

#11
J. Scott
7-28-03

For: TEST METHOD OF ELECTRO-OPTICAL DEVICE, TEST CIRCUIT OF ELECTRO-OPTICAL DEVICE, ELECTRO-OPTICAL DEVICE, AND ELECTRONIC EQUIPMENT

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed more than three months after the U.S. filing date AND after the mailing date of the first Office Action on the merits, but before the mailing date of a Final Rejection, Notice of Allowance or other action that closes prosecution (e.g., Quayle Action).
- ☒ a. I hereby certify that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(1).
- ☒ 1. The references 1-3 were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.

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- ☒ 2. English-language Abstracts of the non-English language references 2 and 3 are attached hereto.
- ☒ 3. A computer-generated English translation of the following Japanese Patent Publication has been obtained from the website of the Japanese Patent Office ([<http://www.jpo.go.jp>]), and is attached, but has not been reviewed for accuracy. See Reference 2.

Respectfully submitted,



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Date: July 21, 2003

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PATENT & TRADEMARK OFFICEATTY DOCKET NO.
110954APPLICATION NO.
09/994,675

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT
Shin FUJITAFILING DATE
November 28, 2001GROUP
2829

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	1	5,576,730	11/1996	Shimada et al.		

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
	2	11-271806 A w/Abstract & Translation	08/1999	Japan		
	3	WO 92/15891 w/Abstract	09/1992	WIPO		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	4	Singapore Search Report performed by Austrian Patent Office

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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